

64M-BIT CMOS LOW-VOLTAGE DUAL OPERATION FLASH MEMORY
4M-WORD BY 16-BIT (WORD MODE)
PAGE MODE
Description

The μ PD29F064115-X is a flash memory organized of 67,108,864 bits and 142 sectors. Sectors of this memory can be erased at a low voltage (1.65 to 1.95 V, 1.8 to 2.1 V) supplied from a power source, or the contents of the entire chip can be erased. Memory organization is 4,194,304 words \times 16 bits, so that the memory can be programmed in word units. μ PD29F064115-X can be read high speed with page mode.

The μ PD29F064115-X can be read while its contents are being erased or programmed. The memory cell is divided into four banks. While sectors in any bank are being erased or programmed, data can be read from the other three banks thanks to the simultaneous execution architecture. The banks are 8M bits, 24M bits, 24M bits and 8M bits.

Input /output voltage is supplied to 2.7 to 3.3 V.

Because the μ PD29F064115-X enables the boot sector to be erased, it is ideal for storing a boot program. In addition, program code that controls the flash memory can be also stored, and the program code can be programmed or erased without the need to load it into RAM. 16 small sectors for storing parameters are provided, each of which can be erased in 4K words units.

Once a program or erase command sequence has been executed, an automatic program or automatic erase function internally executes program or erase and verification automatically. The programming time is about 0.5 seconds per sector. The erase time is less than 1 second per sector.

Because the μ PD29F064115-X can be electrically erased or programmed by writing an instruction, data can be reprogrammed on-board after the flash memory has been installed in a system, making it suitable for a wide range of applications.

This flash memory is packed in 48-pin PLASTIC TSOP (I), 63-pin TAPE FBGA and 85-pin TAPE FBGA.

Features

- Four bank organization enabling simultaneous execution of program / erase and read
- High-speed read with page mode
- Bank organization : 4 banks (8M bits + 24M bits + 24M bits + 8M bits)
- Memory organization : 4,194,304 words \times 16 bits
- Sector organization : 142 sectors (4K words \times 16 sectors, 32K words \times 126 sectors)
The boot sector is located at the highest address (sector) and the lowest address (sector)
- 3-state output
- Automatic program
 - Program suspend / resume
- Unlock bypass program
- Automatic erase
 - Chip erase
 - Sector erase (sectors can be combined freely)
 - Erase suspend / resume
- Program / Erase completion detection
 - Detection through data polling and toggle bits
 - Detection through RY (/BY) pin

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Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.

- Sector group protection
 - Any sector group can be protected
 - Any protected sector group can be temporary unprotected
 - Any sector group can be unprotected
- Sectors can be used for boot application
- Hardware reset and standby using /RESET pin
- Automatic sleep mode
- Boot block sector protect by /WP (ACC) pin
- Extra One Time Protect Sector provided

μPD29F064115	Access time ns (MAX.)	Operating supply voltage V		Power supply current (MAX.)		
		Chip V _{CC}	I/O V _{CCQ}	At active mA		At standby μA
				Read	Program / Erase	
-DB80X, -DB85X	80, 85	1.95 ± 0.15	3.0 ± 0.3	20	35	25
-EB80X ^{Note} , -EB85X, -EB90X	80 ^{Note} , 85, 90	1.8 ± 0.15		15	25	

Note Under Development

- Program / erase time
 - Program : 11.0 μs / word (TYP.)
 - Sector erase :
 - Program / erase cycle : 100,000 cycle
 - 0.15 s (TYP.) (4K words sector), 0.5 s (TYP.) (32K words sector)
 - Program / erase cycle : 300,000 cycle
 - 0.5 s (TYP.) (4K words sector), 0.7 s (TYP.) (32K words sector)
- Program / erase cycle : 300,000 cycle (MIN.)

Ordering Information

Part number	Access time ns (MAX.)	Operating supply voltage V		Operating temperature °C	Package
		Chip V _{CC}	I/O V _{CCQ}		
μPD29F064115GZ-DB80X-MJH	80	1.95 ± 0.15	3.0 ± 0.3	-25 to +85	48-pin PLASTIC TSOP (I) (12 × 20) (Normal bent)
μPD29F064115GZ-DB85X-MJH	85				63-pin TAPE FBGA (11 × 8)
μPD29F064115F9-DB80X-CD6	80				85-pin TAPE FBGA (11 × 8)
μPD29F064115F9-DB85X-CD6	85				
μPD29F064115F9-DB80X-CD5	80				
μPD29F064115F9-DB85X-CD5	85				
μPD29F064115GZ-EB85X-MJH	85	1.8 ± 0.15			48-pin PLASTIC TSOP (I) (12 × 20) (Normal bent)
μPD29F064115GZ-EB90X-MJH	90				63-pin TAPE FBGA (11 × 8)
μPD29F064115F9-EB85X-CD6	85				85-pin TAPE FBGA (11 × 8)
μPD29F064115F9-EB90X-CD6	90				
μPD29F064115F9-EB85X-CD5	85				
μPD29F064115F9-EB90X-CD5	90				

Pin Configurations

/xxx indicates active low signal.

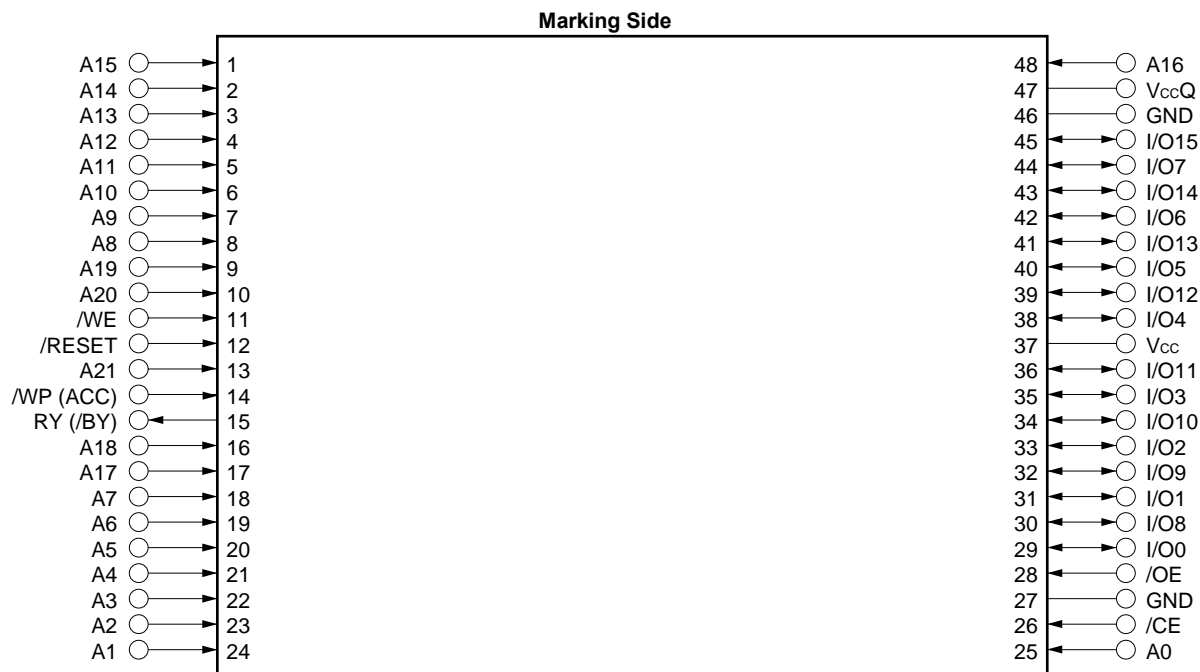
48-pin PLASTIC TSOP (I) (12 × 20) (Normal bent)

[μPD29F064115GZ-DB80X-MJH]

[μPD29F064115GZ-DB85X-MJH]

[μPD29F064115GZ-EB85X-MJH]

[μPD29F064115GZ-EB90X-MJH]



- A0 to A21 : Address inputs
- I/O0 to I/O15 : Data Inputs / Outputs
- /CE : Chip Enable
- /WE : Write Enable
- /OE : Output Enable
- /RESET : Hardware reset input
- RY (/BY) : Ready (Busy) output
- /WP (ACC) : Write Protect (Accelerated) input
- Vcc : Supply Voltage
- VccQ : Input / Output Supply Voltage
- GND : Ground

Remark Refer to **Package Drawings** for the 1-pin index mark.

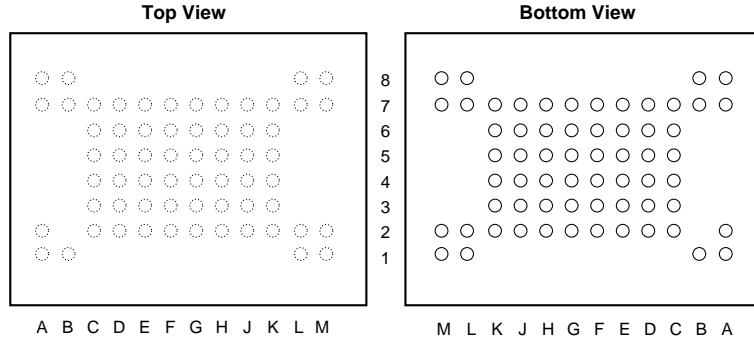
63-pin TAPE FBGA (11 × 8)

[μPD29F064115F9-DB80X-CD6]

[μPD29F064115F9-DB85X-CD6]

[μPD29F064115F9-EB85X-CD6]

[μPD29F064115F9-EB90X-CD6]



Top View

	A	B	C	D	E	F	G	H	J	K	L	M	
8	NC	NC										NC	NC
7	NC	NC	A13	A12	A14	A15	A16	V _{cc} Q	I/O15	GND	NC	NC	
6			A9	A8	A10	A11	I/O7	I/O14	I/O13	I/O6			
5			/WE	/RESET	A21	A19	I/O5	I/O12	V _{cc}	I/O4			
4			RY(/BY)	/WP(ACC)	A18	A20	I/O2	I/O10	I/O11	I/O3			
3			A7	A17	A6	A5	I/O0	I/O8	I/O9	I/O1			
2	NC		A3	A4	A2	A1	A0	/CE	/OE	GND	NC	NC	
1	NC	NC									NC	NC	

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- I/O0 to I/O15 : Data Inputs / Outputs
- /CE : Chip Enable
- /WE : Write Enable
- /OE : Output Enable
- /RESET : Hardware reset input
- RY (/BY) : Ready (Busy) output
- /WP (ACC) : Write Protect (Accelerated) input
- V_{cc} : Supply Voltage
- V_{cc}Q : Input / Output Supply Voltage
- GND : Ground
- NC ^{Note} : No Connection

Note Some signals can be applied because this pin is not connected to the inside of the chip.

Remark Refer to **Package Drawings** for the index mark.

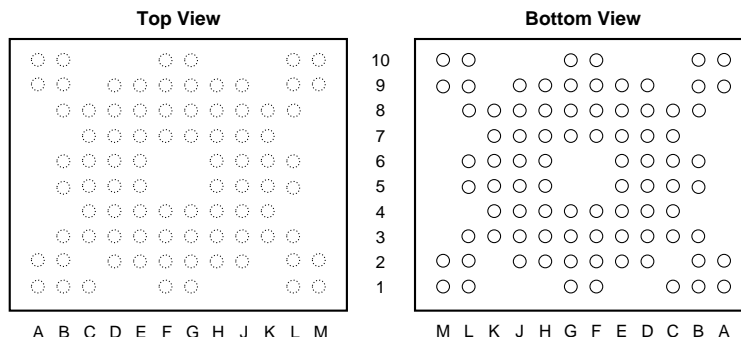
85-pin TAPE FBGA (11 × 8)

[μPD29F064115F9-DB80X-CD5]

[μPD29F064115F9-DB85X-CD5]

[μPD29F064115F9-EB85X-CD5]

[μPD29F064115F9-EB90X-CD5]



Top View

	A	B	C	D	E	F	G	H	J	K	L	M
10	NC	NC				NC	NC				NC	NC
9	NC	NC		A15	A21	NC	A16	NC	GND		NC	NC
8		NC	A11	A12	A13	A14	NC	I/O15	I/O7	I/O14	NC	
7			A8	A19	A9	A10	I/O6	I/O13	I/O12	I/O5		
6		NC	/WE	NC	A20			I/O4	NC	V _{ccQ}	NC	
5		NC	/WP(ACC)/RESET	RY(/BY)				I/O3	V _{cc}	I/O11	NC	
4			NC	NC	A18	A17	I/O1	I/O9	I/O10	I/O2		
3		NC	A7	A6	A5	A4	GND	/OE	I/O0	I/O8	NC	
2	NC	NC		A3	A2	A1	A0	/CE	NC		NC	NC
1	NC	NC	NC			NC	NC				NC	NC

- A0 to A21 : Address inputs
- I/O0 to I/O15 : Data Inputs / Outputs
- /CE : Chip Enable
- /WE : Write Enable
- /OE : Output Enable
- /RESET : Hardware reset input
- RY (/BY) : Ready (Busy) output
- /WP (ACC) : Write Protect (Accelerated) input
- V_{cc} : Supply Voltage
- V_{ccQ} : Input / Output Supply Voltage
- GND : Ground
- NC ^{Note} : No Connection

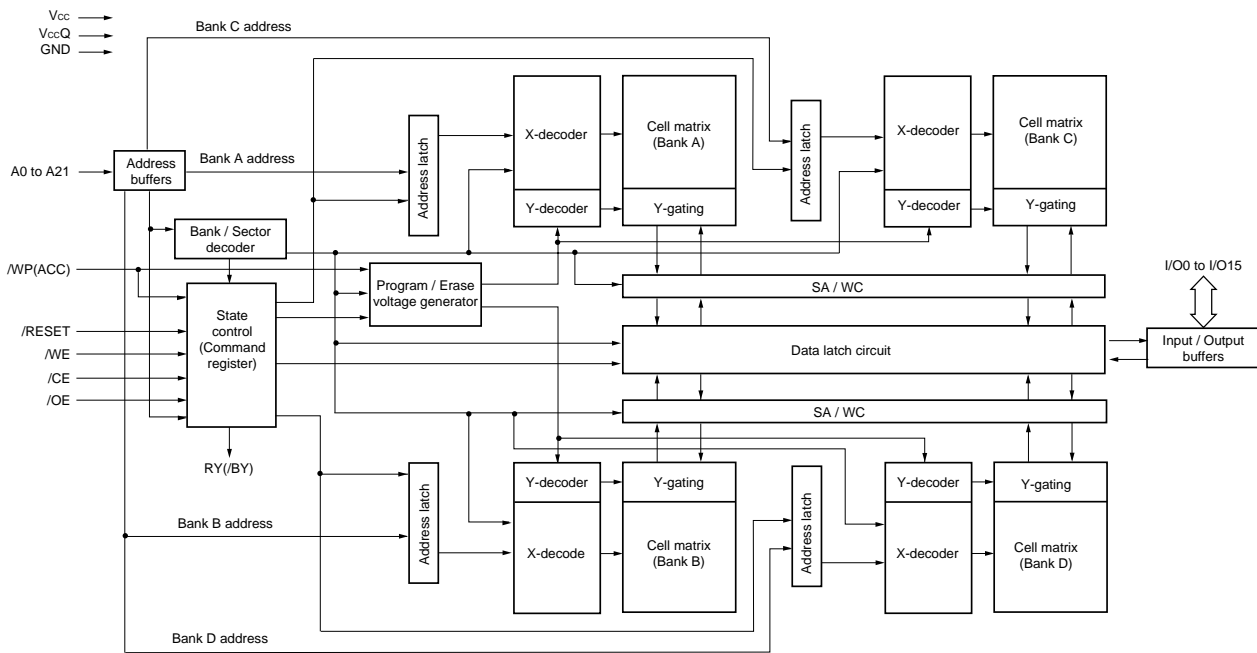
Note Some signals can be applied because this pin is not connected to the inside of the chip.

Remark Refer to **Package Drawings** for the index mark.

INPUT / OUTPUT PIN FUNCTION

Refer to **PAGE MODE FLASH MEMORY, BURST MODE FLASH MEMORY Information (M15451E)**.

Block Diagram



Sector Organization / Sector Address Table

(1/4)

Bank	Sector Organization K words	Address	Sectors Address	Sector Address Table									
				Bank Address Table			A18	A17	A16	A15	A14	A13	A12
				A21	A20	A19							
Bank D	4	3FFFFFH 3FF000H	SA141	1	1	1	1	1	1	1	1	1	1
	4	3FEFFFFH 3FE000H	SA140	1	1	1	1	1	1	1	1	1	0
	4	3FDFFFFH 3FD000H	SA139	1	1	1	1	1	1	1	1	0	1
	4	3FCFFFFH 3FC000H	SA138	1	1	1	1	1	1	1	1	0	0
	4	3FBFFFFH 3FB000H	SA137	1	1	1	1	1	1	1	0	1	1
	4	3FAFFFFH 3FA000H	SA136	1	1	1	1	1	1	1	0	1	0
	4	3F9FFFFH 3F9000H	SA135	1	1	1	1	1	1	1	0	0	1
	4	3F8FFFFH 3F8000H	SA134	1	1	1	1	1	1	1	0	0	0
	32	3F7FFFFH 3F0000H	SA133	1	1	1	1	1	1	0	x	x	x
	32	3EFFFFFH 3E8000H	SA132	1	1	1	1	1	0	1	x	x	x
	32	3E7FFFFH 3E0000H	SA131	1	1	1	1	1	0	0	x	x	x
	32	3DFFFFFH 3D8000H	SA130	1	1	1	1	0	1	1	x	x	x
	32	3D7FFFFH 3D0000H	SA129	1	1	1	1	0	1	0	x	x	x
	32	3CFFFFFH 3C8000H	SA128	1	1	1	1	0	0	1	x	x	x
	32	3C7FFFFH 3C0000H	SA127	1	1	1	1	0	0	0	x	x	x
	32	3B7FFFFH 3B8000H	SA126	1	1	1	0	1	1	1	x	x	x
	32	3B7FFFFH 3B0000H	SA125	1	1	1	0	1	1	0	x	x	x
	32	3AFFFFFH 3A8000H	SA124	1	1	1	0	1	0	1	x	x	x
	32	3A7FFFFH 3A0000H	SA123	1	1	1	0	1	0	0	x	x	x
	32	39FFFFFH 398000H	SA122	1	1	1	0	0	1	1	x	x	x
	32	397FFFFH 390000H	SA121	1	1	1	0	0	1	0	x	x	x
	32	38FFFFFH 388000H	SA120	1	1	1	0	0	0	1	x	x	x
	32	387FFFFH 380000H	SA119	1	1	1	0	0	0	0	x	x	x
	Bank C	32	37FFFFFH 378000H	SA118	1	1	0	1	1	1	1	x	x
32		377FFFFH 370000H	SA117	1	1	0	1	1	1	0	x	x	x
32		36FFFFFH 368000H	SA116	1	1	0	1	1	0	1	x	x	x
32		367FFFFH 360000H	SA115	1	1	0	1	1	0	0	x	x	x
32		35FFFFFH 358000H	SA114	1	1	0	1	0	1	1	x	x	x
32		357FFFFH 350000H	SA113	1	1	0	1	0	1	0	x	x	x
32		34FFFFFH 348000H	SA112	1	1	0	1	0	0	1	x	x	x
32		347FFFFH 340000H	SA111	1	1	0	1	0	0	0	x	x	x
32		33FFFFFH 338000H	SA110	1	1	0	0	1	1	1	x	x	x
32		337FFFFH 330000H	SA109	1	1	0	0	1	1	0	x	x	x
32		32FFFFFH 328000H	SA108	1	1	0	0	1	0	1	x	x	x
32		327FFFFH 320000H	SA107	1	1	0	0	1	0	0	x	x	x
32		31FFFFFH 318000H	SA106	1	1	0	0	0	1	1	x	x	x

Sector Organization / Sector Address Table

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Bank	Sector Organization K words	Address	Sectors Address	Sector Address Table									
				Bank Address Table			A18	A17	A16	A15	A14	A13	A12
				A21	A20	A19							
Bank C	32	317FFFH 310000H	SA105	1	1	0	0	0	1	0	x	x	x
	32	30FFFFH 308000H	SA104	1	1	0	0	0	0	1	x	x	x
	32	307FFFH 300000H	SA103	1	1	0	0	0	0	0	x	x	x
	32	2FFFFFH 2F8000H	SA102	1	0	1	1	1	1	1	x	x	x
	32	2F7FFFH 2F0000H	SA101	1	0	1	1	1	1	0	x	x	x
	32	2EFFFFH 2E8000H	SA100	1	0	1	1	1	0	1	x	x	x
	32	2E7FFFH 2E0000H	SA99	1	0	1	1	1	0	0	x	x	x
	32	2DFFFFH 2D8000H	SA98	1	0	1	1	0	1	1	x	x	x
	32	2D7FFFH 2D0000H	SA97	1	0	1	1	0	1	0	x	x	x
	32	2CFFFFH 2C8000H	SA96	1	0	1	1	0	0	1	x	x	x
	32	2C7FFFH 2C0000H	SA95	1	0	1	1	0	0	0	x	x	x
	32	2BFFFFH 2B8000H	SA94	1	0	1	0	1	1	1	x	x	x
	32	2B7FFFH 2B0000H	SA93	1	0	1	0	1	1	0	x	x	x
	32	2AFFFFH 2A8000H	SA92	1	0	1	0	1	0	1	x	x	x
	32	2A7FFFH 2A0000H	SA91	1	0	1	0	1	0	0	x	x	x
	32	29FFFFH 298000H	SA90	1	0	1	0	0	1	1	x	x	x
	32	297FFFH 290000H	SA89	1	0	1	0	0	1	0	x	x	x
	32	28FFFFH 288000H	SA88	1	0	1	0	0	0	1	x	x	x
	32	287FFFH 280000H	SA87	1	0	1	0	0	0	0	x	x	x
	32	27FFFFH 278000H	SA86	1	0	0	1	1	1	1	x	x	x
	32	277FFFH 270000H	SA85	1	0	0	1	1	1	0	x	x	x
	32	26FFFFH 268000H	SA84	1	0	0	1	1	0	1	x	x	x
	32	267FFFH 260000H	SA83	1	0	0	1	1	0	0	x	x	x
	32	25FFFFH 258000H	SA82	1	0	0	1	0	1	1	x	x	x
	32	257FFFH 250000H	SA81	1	0	0	1	0	1	0	x	x	x
	32	24FFFFH 248000H	SA80	1	0	0	1	0	0	1	x	x	x
	32	247FFFH 240000H	SA79	1	0	0	1	0	0	0	x	x	x
	32	23FFFFH 238000H	SA78	1	0	0	0	1	1	1	x	x	x
	32	237FFFH 230000H	SA77	1	0	0	0	1	1	0	x	x	x
	32	22FFFFH 228000H	SA76	1	0	0	0	1	0	1	x	x	x
	32	227FFFH 220000H	SA75	1	0	0	0	1	0	0	x	x	x
	32	21FFFFH 218000H	SA74	1	0	0	0	0	1	1	x	x	x
32	217FFFH 210000H	SA73	1	0	0	0	0	1	0	x	x	x	
32	20FFFFH 208000H	SA72	1	0	0	0	0	0	1	x	x	x	
32	207FFFH 200000H	SA71	1	0	0	0	0	0	0	x	x	x	

Sector Organization / Sector Address Table

(3/4)

Bank	Sector Organization K words	Address	Sectors Address	Sector Address Table									
				Bank Address Table			A18	A17	A16	A15	A14	A13	A12
				A21	A20	A19							
Bank B	32	1FFFFFH 1F8000H	SA70	0	1	1	1	1	1	1	x	x	x
	32	1F7FFFH 1F0000H	SA69	0	1	1	1	1	1	0	x	x	x
	32	1EFFFFH 1E8000H	SA68	0	1	1	1	1	0	1	x	x	x
	32	1E7FFFH 1E0000H	SA67	0	1	1	1	1	0	0	x	x	x
	32	1DFFFFH 1D8000H	SA66	0	1	1	1	0	1	1	x	x	x
	32	1D7FFFH 1D0000H	SA65	0	1	1	1	0	1	0	x	x	x
	32	1CFFFFH 1C8000H	SA64	0	1	1	1	0	0	1	x	x	x
	32	1C7FFFH 1C0000H	SA63	0	1	1	1	0	0	0	x	x	x
	32	1BFFFFH 1B8000H	SA62	0	1	1	0	1	1	1	x	x	x
	32	1B7FFFH 1B0000H	SA61	0	1	1	0	1	1	0	x	x	x
	32	1AFFFFH 1A8000H	SA60	0	1	1	0	1	0	1	x	x	x
	32	1A7FFFH 1A0000H	SA59	0	1	1	0	1	0	0	x	x	x
	32	19FFFFH 198000H	SA58	0	1	1	0	0	1	1	x	x	x
	32	197FFFH 190000H	SA57	0	1	1	0	0	1	0	x	x	x
	32	18FFFFH 188000H	SA56	0	1	1	0	0	0	1	x	x	x
	32	187FFFH 180000H	SA55	0	1	1	0	0	0	0	x	x	x
	32	17FFFFH 178000H	SA54	0	1	0	1	1	1	1	x	x	x
	32	177FFFH 170000H	SA53	0	1	0	1	1	1	0	x	x	x
	32	16FFFFH 168000H	SA52	0	1	0	1	1	0	1	x	x	x
	32	167FFFH 160000H	SA51	0	1	0	1	1	0	0	x	x	x
	32	15FFFFH 158000H	SA50	0	1	0	1	0	1	1	x	x	x
	32	157FFFH 150000H	SA49	0	1	0	1	0	1	0	x	x	x
	32	14FFFFH 148000H	SA48	0	1	0	1	0	0	1	x	x	x
	32	147FFFH 140000H	SA47	0	1	0	1	0	0	0	x	x	x
	32	13FFFFH 138000H	SA46	0	1	0	0	1	1	1	x	x	x
	32	137FFFH 130000H	SA45	0	1	0	0	1	1	0	x	x	x
	32	12FFFFH 128000H	SA44	0	1	0	0	1	0	1	x	x	x
	32	127FFFH 120000H	SA43	0	1	0	0	1	0	0	x	x	x
	32	11FFFFH 118000H	SA42	0	1	0	0	0	1	1	x	x	x
	32	117FFFH 110000H	SA41	0	1	0	0	0	1	0	x	x	x
	32	10FFFFH 108000H	SA40	0	1	0	0	0	0	1	x	x	x
	32	107FFFH 100000H	SA39	0	1	0	0	0	0	0	x	x	x
32	0FFFFFH 0F8000H	SA38	0	0	1	1	1	1	1	x	x	x	
32	0F7FFFH 0F0000H	SA37	0	0	1	1	1	1	0	x	x	x	
32	0EFFFFH 0E8000H	SA36	0	0	1	1	1	0	1	x	x	x	
32	0E7FFFH 0E0000H	SA35	0	0	1	1	1	0	0	x	x	x	

Sector Organization / Sector Address Table

(4/4)

Bank	Sector Organization K words	Address	Sectors Address	Sector Address Table									
				Bank Address Table			A18	A17	A16	A15	A14	A13	A12
				A21	A20	A19							
Bank B	32	0DFFFFH 0D8000H	SA34	0	0	1	1	0	1	1	x	x	x
	32	0D7FFFH 0D0000H	SA33	0	0	1	1	0	1	0	x	x	x
	32	0CFFFFH 0C8000H	SA32	0	0	1	1	0	0	1	x	x	x
	32	0C7FFFH 0C0000H	SA31	0	0	1	1	0	0	0	x	x	x
	32	0BFFFFH 0B8000H	SA30	0	0	1	0	1	1	1	x	x	x
	32	0B7FFFH 0B0000H	SA29	0	0	1	0	1	1	0	x	x	x
	32	0AFFFFH 0A8000H	SA28	0	0	1	0	1	0	1	x	x	x
	32	0A7FFFH 0A0000H	SA27	0	0	1	0	1	0	0	x	x	x
	32	09FFFFH 098000H	SA26	0	0	1	0	0	1	1	x	x	x
	32	097FFFH 090000H	SA25	0	0	1	0	0	1	0	x	x	x
	32	08FFFFH 088000H	SA24	0	0	1	0	0	0	1	x	x	x
	32	087FFFH 080000H	SA23	0	0	1	0	0	0	0	x	x	x
	Bank A	32	07FFFFH 078000H	SA22	0	0	0	1	1	1	1	x	x
32		077FFFH 070000H	SA21	0	0	0	1	1	1	0	x	x	x
32		06FFFFH 068000H	SA20	0	0	0	1	1	0	1	x	x	x
32		067FFFH 060000H	SA19	0	0	0	1	1	0	0	x	x	x
32		05FFFFH 058000H	SA18	0	0	0	1	0	1	1	x	x	x
32		057FFFH 050000H	SA17	0	0	0	1	0	1	0	x	x	x
32		04FFFFH 048000H	SA16	0	0	0	1	0	0	1	x	x	x
32		047FFFH 040000H	SA15	0	0	0	1	0	0	0	x	x	x
32		03FFFFH 038000H	SA14	0	0	0	0	1	1	1	x	x	x
32		037FFFH 030000H	SA13	0	0	0	0	1	1	0	x	x	x
32		02FFFFH 028000H	SA12	0	0	0	0	1	0	1	x	x	x
32		027FFFH 020000H	SA11	0	0	0	0	1	0	0	x	x	x
32		01FFFFH 018000H	SA10	0	0	0	0	0	1	1	x	x	x
32		017FFFH 010000H	SA9	0	0	0	0	0	1	0	x	x	x
32		00FFFFH 008000H	SA8	0	0	0	0	0	0	1	x	x	x
4		007FFFH 007000H	SA7	0	0	0	0	0	0	0	1	1	1
4		006FFFH 006000H	SA6	0	0	0	0	0	0	0	1	1	0
4		005FFFH 005000H	SA5	0	0	0	0	0	0	0	1	0	1
4		004FFFH 004000H	SA4	0	0	0	0	0	0	0	1	0	0
4		003FFFH 003000H	SA3	0	0	0	0	0	0	0	0	1	1
4	002FFFH 002000H	SA2	0	0	0	0	0	0	0	0	1	0	
4	001FFFH 001000H	SA1	0	0	0	0	0	0	0	0	0	1	
4	000FFFH 000000H	SA0	0	0	0	0	0	0	0	0	0	0	

Sector Group Address Table

(1/2)

Sector group	A21	A20	A19	A18	A17	A16	A15	A14	A13	A12	Size	Sector
SGA0	0	0	0	0	0	0	0	0	0	0	4K words (1 Sector)	SA0
SGA1	0	0	0	0	0	0	0	0	0	1	4K words (1 Sector)	SA1
SGA2	0	0	0	0	0	0	0	0	1	0	4K words (1 Sector)	SA2
SGA3	0	0	0	0	0	0	0	0	1	1	4K words (1 Sector)	SA3
SGA4	0	0	0	0	0	0	0	1	0	0	4K words (1 Sector)	SA4
SGA5	0	0	0	0	0	0	0	1	0	1	4K words (1 Sector)	SA5
SGA6	0	0	0	0	0	0	0	1	1	0	4K words (1 Sector)	SA6
SGA7	0	0	0	0	0	0	0	1	1	1	4K words (1 Sector)	SA7
SGA8	0	0	0	0	0	0	1	×	×	×	96K words (3 Sectors)	SA8 to SA10
						1	0					
						1	1					
SGA9	0	0	0	0	1	×	×	×	×	×	128K words (4 Sectors)	SA11 to SA14
SGA10	0	0	0	1	0	×	×	×	×	×	128K words (4 Sectors)	SA15 to SA18
SGA11	0	0	0	1	1	×	×	×	×	×	128K words (4 Sectors)	SA19 to SA22
SGA12	0	0	1	0	0	×	×	×	×	×	128K words (4 Sectors)	SA23 to SA26
SGA13	0	0	1	0	1	×	×	×	×	×	128K words (4 Sectors)	SA27 to SA30
SGA14	0	0	1	1	0	×	×	×	×	×	128K words (4 Sectors)	SA31 to SA34
SGA15	0	0	1	1	1	×	×	×	×	×	128K words (4 Sectors)	SA35 to SA38
SGA16	0	1	0	0	0	×	×	×	×	×	128K words (4 Sectors)	SA39 to SA42
SGA17	0	1	0	0	1	×	×	×	×	×	128K words (4 Sectors)	SA43 to SA46
SGA18	0	1	0	1	0	×	×	×	×	×	128K words (4 Sectors)	SA47 to SA50
SGA19	0	1	0	1	1	×	×	×	×	×	128K words (4 Sectors)	SA51 to SA54
SGA20	0	1	1	0	0	×	×	×	×	×	128K words (4 Sectors)	SA55 to SA58
SGA21	0	1	1	0	1	×	×	×	×	×	128K words (4 Sectors)	SA59 to SA62
SGA22	0	1	1	1	0	×	×	×	×	×	128K words (4 Sectors)	SA63 to SA66
SGA23	0	1	1	1	1	×	×	×	×	×	128K words (4 Sectors)	SA67 to SA70

Remark × : V_{IH} or V_{IL}

Sector Group Address Table

(2/2)

Sector group	A21	A20	A19	A18	A17	A16	A15	A14	A13	A12	Size	Sector
SGA24	1	0	0	0	0	×	×	×	×	×	128K words (4 Sectors)	SA71 to SA74
SGA25	1	0	0	0	1	×	×	×	×	×	128K words (4 Sectors)	SA75 to SA78
SGA26	1	0	0	1	0	×	×	×	×	×	128K words (4 Sectors)	SA79 to SA82
SGA27	1	0	0	1	1	×	×	×	×	×	128K words (4 Sectors)	SA83 to SA86
SGA28	1	0	1	0	0	×	×	×	×	×	128K words (4 Sectors)	SA87 to SA90
SGA29	1	0	1	0	1	×	×	×	×	×	128K words (4 Sectors)	SA91 to SA94
SGA30	1	0	1	1	0	×	×	×	×	×	128K words (4 Sectors)	SA95 to SA98
SGA31	1	0	1	1	1	×	×	×	×	×	128K words (4 Sectors)	SA99 to SA102
SGA32	1	1	0	0	0	×	×	×	×	×	128K words (4 Sectors)	SA103 to SA106
SGA33	1	1	0	0	1	×	×	×	×	×	128K words (4 Sectors)	SA107 to SA110
SGA34	1	1	0	1	0	×	×	×	×	×	128K words (4 Sectors)	SA111 to SA114
SGA35	1	1	0	1	1	×	×	×	×	×	128K words (4 Sectors)	SA115 to SA118
SGA36	1	1	1	0	0	×	×	×	×	×	128K words (4 Sectors)	SA119 to SA122
SGA37	1	1	1	0	1	×	×	×	×	×	128K words (4 Sectors)	SA123 to SA126
SGA38	1	1	1	1	0	×	×	×	×	×	128K words (4 Sectors)	SA127 to SA130
SGA39	1	1	1	1	1	0	0	×	×	×	96K words (3 Sectors)	SA131 to SA133
						0	1					
						1	0					
SGA40	1	1	1	1	1	1	1	0	0	0	4K words (1 Sector)	SA134
SGA41	1	1	1	1	1	1	1	0	0	1	4K words (1 Sector)	SA135
SGA42	1	1	1	1	1	1	1	0	1	0	4K words (1 Sector)	SA136
SGA43	1	1	1	1	1	1	1	0	1	1	4K words (1 Sector)	SA137
SGA44	1	1	1	1	1	1	1	1	0	0	4K words (1 Sector)	SA138
SGA45	1	1	1	1	1	1	1	1	0	1	4K words (1 Sector)	SA139
SGA46	1	1	1	1	1	1	1	1	1	0	4K words (1 Sector)	SA140
SGA47	1	1	1	1	1	1	1	1	1	1	4K words (1 Sector)	SA141

Remark × : V_{IH} or V_{IL}

Product ID Code (Manufacturer Code / Device Code)

Product ID Code	Output code																HEX
	I/O15	I/O14	I/O13	I/O12	I/O11	I/O10	I/O9	I/O8	I/O7	I/O6	I/O5	I/O4	I/O3	I/O2	I/O1	I/O0	
Manufacturer Code	0	0	0	0	0	0	0	0	0	0	0	1	0	0	0	0	0010H
Device code	0	0	1	0	0	0	1	0	0	0	0	1	1	1	0	0	221CH
Sector group protection	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	1	0001H ^{Note}

Note If 0001H is output, the sector group is protected. If 0000H is output, the sector group is unprotected.

Command Sequence

Command sequence	Bus Cycle	1st bus Cycle		2nd bus Cycle		3rd bus Cycle		4th bus Cycle		5th bus Cycle		6th bus Cycle	
		Address	Data	Address	Data	Address	Data	Address	Data	Address	Data	Address	Data
Read / Reset ^{Note 1}	1	xxxH	F0H	RA	RD	-	-	-	-	-	-	-	-
Read / Reset ^{Note 1}	3	555H	AAH	2AAH	55H	555H	F0H	RA	RD	-	-	-	-
Program	4	555H	AAH	2AAH	55H	555H	A0H	PA	PD	-	-	-	-
Program Suspend ^{Note 2}	1	BA	B0H	-	-	-	-	-	-	-	-	-	-
Program Resume ^{Note 3}	1	BA	30H	-	-	-	-	-	-	-	-	-	-
Chip Erase	6	555H	AAH	2AAH	55H	555H	80H	555H	AAH	2AAH	55H	555H	10H
Sector Erase	6	555H	AAH	2AAH	55H	555H	80H	555H	AAH	2AAH	55H	SA	30H
Sector Erase Suspend ^{Note 4, 5}	1	BA	B0H	-	-	-	-	-	-	-	-	-	-
Sector Erase Resume ^{Note 4, 6}	1	BA	30H	-	-	-	-	-	-	-	-	-	-
Unlock Bypass Set	3	555H	AAH	2AAH	55H	555H	20H	-	-	-	-	-	-
Unlock Bypass Program ^{Note 7}	2	xxxH	A0H	PA	PD	-	-	-	-	-	-	-	-
Unlock Bypass Chip Erase ^{Note 7}	2	xxxH	80H	xxxH	10H	-	-	-	-	-	-	-	-
Unlock Bypass Sector Erase ^{Note 7}	2	xxxH	80H	SA	30H	-	-	-	-	-	-	-	-
Unlock Bypass Reset ^{Note 7}	2	xxxH	90H	xxxH	00H ^{Note 11}	-	-	-	-	-	-	-	-
Product ID / Sector Group Protection Information / Read Mode Register Information	3	555H	AAH	2AAH	55H	(BA) 555H	90H	IA	ID	-	-	-	-
Sector Group Protection ^{Note 8}	4	xxxH	60H	SPA	60H	SPA	40H	SPA	SD	-	-	-	-
Sector Group Unprotect ^{Note 9}	4	xxxH	60H	SUA	60H	SUA	40H	SUA	SD	-	-	-	-
Extra One Time Protect Sector Entry	3	555H	AAH	2AAH	55H	555H	88H	-	-	-	-	-	-
Extra One Time Protect Sector Reset ^{Note 10}	4	555H	AAH	2AAH	55H	555H	90H	xxxH	00H	-	-	-	-
Extra One Time Protect Sector Program ^{Note 10}	4	555H	AAH	2AAH	55H	555H	A0H	PA	PD	-	-	-	-
Extra One Time Protect Sector Erase ^{Note 10}	6	555H	AAH	2AAH	55H	555H	80H	555H	AAH	2AAH	55H	EOTPSA	30H
Extra One Time Protect Sector Protection ^{Note 10}	4	xxxH	60H	EOTPSA	60H	EOTPSA	40H	EOTPSA	SD	-	-	-	-
Read Mode Register Set	3	555H	AAH	2AAH	55H	REGD	C0H	-	-	-	-	-	-

- Notes 1.** Both these read / reset commands reset the device to the read mode.
2. Programming is suspended if B0H is input to the bank address being programmed to in a program operation.
 3. Programming is resumed if 30H is input to the bank address being suspended to in a program-suspend operation.
 4. If automatic erase resume and suspend are repeated at intervals of less than 100 μs, since it will become suspend operation, without starting automatic erase, the erase operation may not be correctly completed.
 5. Erasure is suspended if B0H is input to the bank address being erased in a sector erase operation.
 6. Erasure is resumed if 30H is input to the bank address being suspended in a sector-erase-suspend operation.
 7. Valid only in the Unlock Bypass mode.
 8. Valid only in /RESET = V_{DD} (except in the Extra One Time Protect Sector mode).
 9. The command sequence that protects a sector group is excluded.
 10. Valid only in the Extra One Time Protect Sector mode.
 11. This command can be used even if this data is F0H.

Remarks 1. The system should generate the following address pattern:

555H or 2AAH (A10 to A0)

2. RA : Read address
 RD : Read data
 IA : Address input as follows

Information	A21 to A12	A11 to A4	A3 to A0
Manufacturer code	Bank address	Don't care	0000
Device code	Bank address	Don't care	0001
Sector group protection information	Sector group address	Don't care	0010
Read mode register information	Bank address	Don't care	0100

- ID : Code output. For the manufacture code, device code and sector group protection information, refer to the **Product ID code (Manufacture Code / Device Code)**. For read mode register information, refer to **PAGE MODE FLASH MEMORY, BURST MODE FLASH MEMORY Information (M15451E)**.
- PA : Program address
- PD : Program data
- SA : Erase sector address. The sector to be erased is selected by the combination of A21 to A12. Refer to the **Sector Organization / Sector Address Table**.
- BA : Bank address. Refer to the **Sector Organization / Sector Address Table**.

- ★ SPA : Sector group address to be protected or protection-verified. Set the sector group address (SGA) and (A6, A3, A2, A1, A0) = (V_{IL}, V_{IL}, V_{IL}, V_{IH}, V_{IL}).
Sector group protection can be set for each sector group address. For details, refer to **PAGE MODE FLASH MEMORY, BURST MODE FLASH MEMORY Information (M15451E)**.
Refer to the **Sector Group Address Table** for the sector group address.
- ★ SUA : Sector group address to be unprotected or unprotection-verified. Set the sector group address (SGA) and (A6, A3, A2, A1, A0) = (V_{IH}, V_{IL}, V_{IL}, V_{IH}, V_{IL}).
Sector group unprotect is performed for all sector group using a single command, however, unprotect verification must be performed for each sector group address. For details, refer to **PAGE MODE FLASH MEMORY, BURST MODE FLASH MEMORY Information (M15451E)**.
Refer to the **Sector Group Address Table** for the sector group address.
- EOTPSA : Extra One Time Protect Sector area addresses. These addresses are 000000H to 007FFFH.
- SD : Data for verifying whether sector groups read from the address specified by SPA, SUA, EOTPSA are protected or unprotected.
- REGD : Read mode register information. Description for setting, refer to **PAGE MODE FLASH MEMORY, BURST MODE FLASH MEMORY Information (M15451E)**.
3. The sector group address is don't care except when a program / erase address or read address are selected.
 4. For the operation of bus, refer to **PAGE MODE FLASH MEMORY, BURST MODE FLASH MEMORY Information (M15451E)**.
 5. × of address bit indicates V_{IH} or V_{IL}.

BUS OPERATIONS, COMMANDS, HARDWARE SEQUENCE FLAGS, HARDWARE DATA PROTECTION

Refer to **PAGE MODE FLASH MEMORY, BURST MODE FLASH MEMORY Information (M15451E)**.

Electrical Characteristics

Before turning on power, input GND ± 0.2 V to the /RESET pin until $V_{CC} \geq V_{CC}(\text{MIN.})$ and keep that state for 200 μs.

Absolute Maximum Ratings

Parameter	Symbol	Condition		Rating	Unit
Supply voltage	V_{CC}	with respect to GND		-0.5 to +2.4	V
Input / Output supply voltage	V_{CCQ}	with respect to GND		-0.5 to +4.0	V
Input voltage	V_{IN}	with respect to GND	except /WP(ACC), /RESET	-0.5 ^{Note 1} to $V_{CCQ} + 0.5$ ^{Note 2}	V
			/WP(ACC), /RESET	-0.5 ^{Note 1} to +13.0	
Input /Output voltage	V_{IO}	with respect to GND		-0.5 ^{Note 1} to $V_{CCQ} + 0.5$ ^{Note 2}	V
Ambient operation temperature	T_A			-25 to +85	°C
Storage temperature	T_{stg}			-65 to +150	°C
	T_{bias}	at bias		-25 to +85	

- Notes 1.** -2.0 V (MIN.) (pulse width ≤ 20 ns)
2. $V_{CCQ} + 2.0$ V (MAX.) (pulse width ≤ 20 ns)

Caution Exposing the device to stress above those listed in Absolute Maximum Rating could cause permanent damage. The device is not meant to be operated under conditions outside the limits described in the operational section of this specification. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability.

Recommended Operating Conditions

Parameter	Symbol	Test condition	-DB80X, -DB85X		-EB85X, -EB90X		Unit
			MIN.	MAX.	MIN.	MAX.	
Supply voltage	V_{CC}		1.8	2.1	1.65	1.95	V
Input / Output supply voltage	V_{CCQ}		2.7	3.3	2.7	3.3	V
High level input voltage	V_{IH}		2.4	$V_{CCQ} + 0.3$ ^{Note1}	2.4	$V_{CCQ} + 0.3$ ^{Note1}	V
	V_{ID}	High voltage is applied (/RESET)	9.0	11.0	9.0	11.0	
Low level input voltage	V_{IL}		-0.5 ^{Note2}	+0.5	-0.5 ^{Note2}	+0.5	V
Accelerated programming voltage	V_{ACC}	High voltage is applied	8.5	9.5	8.5	9.5	V
Ambient operating temperature	T_A		-25	+85	-25	+85	°C

- Notes 1.** $V_{CCQ} + 0.6$ V (MAX.) (pulse width ≤ 20 ns)
2. -0.6 V (MIN.) (pulse width ≤ 20 ns)

DC Characteristics (Recommended Operating Conditions Unless Otherwise Noted)

(1/2)

Parameter	Symbol	Test condition	-DB80X, -DB85X			Unit			
			MIN.	TYP.	MAX.				
High level output voltage	V _{OH1}	I _{OH} = -2.0 mA, V _{CC} = V _{CC} (MIN.), V _{CCQ} = V _{CCQ} (MIN.)	2.4			V			
	V _{OH2}	I _{OH} = -100 μA, V _{CC} = V _{CC} (MIN.), V _{CCQ} = V _{CCQ} (MIN.)	V _{CCQ} -0.1						
Low level output voltage	V _{OL}	I _{OL} = 4.0 mA, V _{CCQ} = V _{CCQ} (MIN.)			0.45	V			
Input leakage current	I _{LI1}	V _{IN} = GND to V _{CCQ} , V _{CCQ} = V _{CCQ} (MAX.)			1.0	μA			
	High voltage is applied I _{LI2}	/RESET = 11.0 V			35				
I/O leakage current	I _{LO}	V _{I/O} = GND to V _{CCQ} , V _{CCQ} = V _{CCQ} (MAX.)			1.0	μA			
Power supply current	Read	I _{CC1}	/CE = V _{IL} , /OE = V _{IH} , Cycle = 5 MHz, I _{OUT} = 0 mA				10	20	mA
	Program, Erase	I _{CC2}	/CE = V _{IL} , /OE = V _{IH} , Automatic programming / erase					35	mA
	Standby	I _{CC3}	V _{CC} = V _{CC} (MAX.), /OE = V _{IL} , /CE = /RESET = /WP(ACC) = V _{CCQ} ± 0.3 V				15	25	μA
	Standby / Reset	I _{CC4}	V _{CC} = V _{CC} (MAX.), /RESET = GND ± 0.2 V				15	25	μA
	Automatic sleep mode	I _{CC5}	V _{IH} = V _{CCQ} ± 0.2 V, V _{IL} = GND ± 0.2 V				15	25	μA
	Read during programming	I _{CC6}	V _{IH} = V _{CCQ} ± 0.2 V, V _{IL} = GND ± 0.2 V					55	mA
	Read during erasing	I _{CC7}	V _{IH} = V _{CCQ} ± 0.2 V, V _{IL} = GND ± 0.2 V					55	mA
	Programming during suspend	I _{CC8}	/CE = V _{IL} , /OE = V _{IH} , Automatic programming during suspend					35	mA
	Accelerated programming	I _{ACC}	/WP (ACC) pin				5	10	mA
	V _{CC}				15	35			
Low V _{CC} lock-out voltage ^{Note}	V _{LKO}		1.0					V	

Note When V_{CC} is equal to or lower than V_{LKO}, the device ignores all write cycles. Refer to **PAGE MODE FLASH MEMORY, BURST MODE FLASH MEMORY Information (M15451E)**.

Remark V_{IN} : Input voltage, V_{I/O} : Input / Output voltage

DC Characteristics (Recommended Operating Conditions Unless Otherwise Noted)

(2/2)

Parameter	Symbol	Test condition	-EB85X, -EB90X			Unit			
			MIN.	TYP.	MAX.				
High level output voltage	V _{OH1}	I _{OH} = -2.0 mA, V _{CC} = V _{CC} (MIN.), V _{CCQ} = V _{CCQ} (MIN.)	2.4			V			
	V _{OH2}	I _{OH} = -100 μA, V _{CC} = V _{CC} (MIN.), V _{CCQ} = V _{CCQ} (MIN.)	V _{CCQ} -0.1						
Low level output voltage	V _{OL}	I _{OL} = 4.0 mA, V _{CCQ} = V _{CCQ} (MIN.)			0.45	V			
Input leakage current	I _{LI1}	V _{IN} = GND to V _{CCQ} , V _{CCQ} = V _{CCQ} (MAX.)			1.0	μA			
	High voltage is applied I _{LI2}	/RESET = 11.0 V			35				
I/O leakage current	I _{LO}	V _{I/O} = GND to V _{CCQ} , V _{CCQ} = V _{CCQ} (MAX.)			1.0	μA			
Power supply current	Read	I _{CC1}	/CE = V _{IL} , /OE = V _{IH} , Cycle = 5 MHz, I _{OUT} = 0 mA				8	15	mA
	Program, Erase	I _{CC2}	/CE = V _{IL} , /OE = V _{IH} , Automatic programming / erase					25	mA
	Standby	I _{CC3}	V _{CC} = V _{CC} (MAX.), /OE = V _{IL} , /CE = /RESET = /WP(ACC) = V _{CCQ} ± 0.3 V				15	25	μA
	Standby / Reset	I _{CC4}	V _{CC} = V _{CC} (MAX.), /RESET = GND ± 0.2 V				15	25	μA
	Automatic sleep mode	I _{CC5}	V _{IH} = V _{CCQ} ± 0.2 V, V _{IL} = GND ± 0.2 V				15	25	μA
	Read during programming	I _{CC6}	V _{IH} = V _{CCQ} ± 0.2 V, V _{IL} = GND ± 0.2 V					40	mA
	Read during erasing	I _{CC7}	V _{IH} = V _{CCQ} ± 0.2 V, V _{IL} = GND ± 0.2 V					40	mA
	Programming during suspend	I _{CC8}	/CE = V _{IL} , /OE = V _{IH} , Automatic programming during suspend					25	mA
	Accelerated programming	I _{ACC}	/WP (ACC) pin				5	10	mA
	V _{CC}				12	25			
Low V _{CC} lock-out voltage ^{Note}	V _{LKO}		1.0					V	

Note When V_{CC} is equal to or lower than V_{LKO}, the device ignores all write cycles. Refer to **PAGE MODE FLASH MEMORY, BURST MODE FLASH MEMORY Information (M15451E)**.

Remark V_{IN} : Input voltage, V_{I/O} : Input / Output voltage

Capacitance (T_A = 25°C, f = 1 MHz)

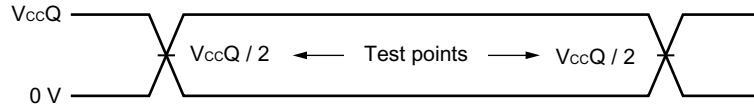
Parameter	Symbol	Test condition	MIN.	TYP.	MAX.	Unit
Input capacitance	C _{IN}	V _{IN} = 0 V		6.0	7.5	pF
Input / Output capacitance	C _{I/O}	V _{I/O} = 0 V		8.5	12.0	pF

- Remarks**
1. V_{IN} : Input voltage, V_{I/O} : Input / Output voltage
 2. These parameters are not 100% tested.

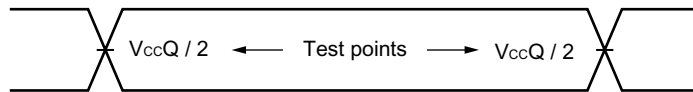
AC Characteristics (Recommended Operating Conditions Unless Otherwise Noted)

AC Test Conditions

Input Waveform (Rise and Fall Time ≤ 5 ns)



Output Waveform



Output Load

1 TTL + 30 pF

Read Cycle

Parameter	Symbol	-DB80X		-DB85X -EB85X		-EB90X		Unit	Note
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Read cycle time	t _{RC}	80		85		90		ns	
Address access time	t _{ACC}		80		85		90	ns	1
Page read cycle time	t _{PRC}	30		30		30		ns	
Page address access time	t _{PACC}		30		30		30	ns	1
/CE access time	t _{CE}		80		85		90	ns	2
/OE access time	t _{OE}		25		25		25	ns	
Output disable time	t _{DF}		25		25		25	ns	
Output hold time	t _{OH}	0		0		0		ns	
/RESET pulse width	t _{RP}	500		500		500		ns	
/RESET hold time before read	t _{RH}	50		50		50		ns	
/RESET low to read mode	At automatic mode	t _{READY}		20		20		20	μs
	Except automatic mode			500		500		500	ns
★ /OE low level time from /WE high level	t _{OEHL}	20		20		20		ns	

Notes 1. /CE = /OE = V_{IL}

2. /OE = V_{IL}

Remark t_{DF} is the time from inactivation of /CE or /OE to high impedance state output.

Write Cycle (Program / Erase)

(1/2)

Parameter	Symbol	-DB80X			-DB85X -EB85X			-EB90X			Unit	Note
		MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.		
Write cycle time	t _{WC}	80			85			90			ns	
Address setup time (/WE to address)	t _{AS}	0			0			0			ns	
Address setup time (/CE to address)	t _{AS}	0			0			0			ns	
Address hold time (/WE to address)	t _{AH}	45			45			45			ns	
Address hold time (/CE to address)	t _{AH}	45			45			45			ns	
Input data setup time	t _{DS}	45			45			45			ns	
Input data hold time	t _{DH}	0			0			0			ns	
/OE hold time	Read	t _{OEH}	0		0			0			ns	
	Toggle bit, Data polling		10		10			10				
Read recovery time before write (/OE to /CE)	t _{GHEL}	0			0			0			ns	
Read recovery time before write (/OE to /WE)	t _{GHWL}	0			0			0			ns	
/WE setup time (/CE to /WE)	t _{WS}	0			0			0			ns	
/CE setup time (/WE to /CE)	t _{CS}	0			0			0			ns	
/WE hold time (/CE to /WE)	t _{WH}	0			0			0			ns	
/CE hold time (/WE to /CE)	t _{CH}	0			0			0			ns	
Write pulse width	t _{WP}	35			35			35			ns	
/CE pulse width	t _{CP}	35			35			35			ns	
Write pulse width high	t _{WPH}	30			30			30			ns	
/CE pulse width high	t _{CPH}	30			30			30			ns	
Word programming operation time	t _{WPG}		11	200		11	200		11	200	μs	
Chip programming operation time	t _{CPG}		47	840		47	840		47	840	s	
Sector erase operation time	4K words sector	t _{SER}	0.15	1.0		0.15	1.0		0.15	1.0	s	1,2
	32K words sector		0.5	1.5		0.5	1.5		0.5	1.5		
	4K words sector		0.5	3.0		0.5	3.0		0.5	3.0		1,3
	32K words sector		0.7	5.0		0.7	5.0		0.7	5.0		
Chip erase operation time	t _{CER}		65.4	205		65.4	205		65.4	205	s	1,2
			96.2	678		96.2	678		96.2	678		1,3
Accelerated programming time	t _{ACCPG}		7	150		7	150		7	150	μs	
Program / erase cycle		300,000			300,000			300,000			cycle	
V _{CC} setup time	t _{VCS}	200			200			200			μs	
RY (/BY) recovery time	t _{RB}	0			0			0			ns	
/RESET pulse width	t _{RP}	500			500			500			ns	
/RESET high-voltage (V _{ID}) hold time from high of RY (/BY) when sector group is temporarily unprotect	t _{RRB}	20			20			20			μs	
/RESET hold time	t _{RH}	50			50			50			ns	

Notes 1. The preprogramming time prior to the erase operation is not included.

2. Program / erase cycle : 100,000 cycles

3. Program / erase cycle : 300,000 cycles

Write Cycle (Program / Erase)

(2/2)

Parameter	Symbol	-DB80X			-DB85X -EB85X			-EB90X			Unit	Note
		MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.		
From completion of automatic program / erase to data output time	t _{EOE}			80			85			90	ns	
RY (/BY) delay time from valid program or erase operation	t _{BUSY}			80			85			90	ns	
Address setup time to /OE low in toggle bit	t _{ASO}	15			15			15			ns	
Address hold time to /CE or /OE high in toggle bit	t _{AHT}	0			0			0			ns	
/CE pulse width high for toggle bit	t _{CEPH}	20			20			20			ns	
/OE pulse width high for toggle bit	t _{OEPH}	20			20			20			ns	
Voltage transition time	t _{VLHT}	4			4			4			μs	1
Rise time to V _{ID} (/RESET)	t _{VIDR}	500			500			500			ns	
Rise time to V _{ACC} (/WP(ACC))	t _{VACCR}	500			500			500			ns	
Erase timeout time	t _{TOW}	50			50			50			μs	2
Erase suspend transition time	t _{SPD}			20			20			20	μs	2

- Notes**
1. Sector group protection only.
 2. Table only.

Write operation (Program / Erase) Performance

Parameter	Description	MIN.	TYP.	MAX.	Unit	Note	
Sector erase time	The preprogramming time prior to the erase operation is not included.	4K words sector		0.15	1.0	s	1
		32K words sector		0.5	1.5		
		4K words sector		0.5	3.0	s	2
		32K words sector		0.7	5.0		
Chip erase time	The preprogramming time prior to the erase operation is not included.			65.4	205	s	1
				96.2	678		
Word programming time	Excludes system-level overhead		11	200	μs		
Chip programming time	Excludes system-level overhead		47	840	s		
Accelerated programming time	Excludes system-level overhead		7	150	μs		
Program / erase cycle		300,000			cycle		

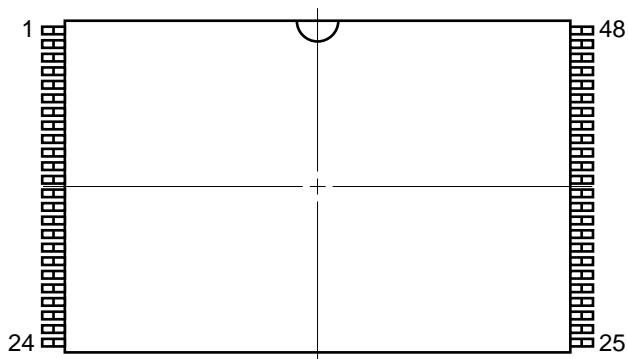
- Notes**
1. Program / erase cycle : 100,000 cycles
 2. Program / erase cycle : 300,000 cycles

TIMING CHARTS, FLOW CHARTS

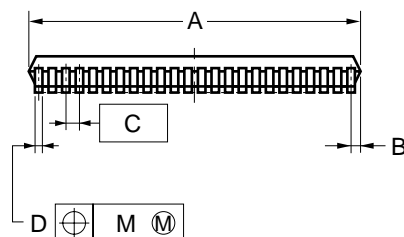
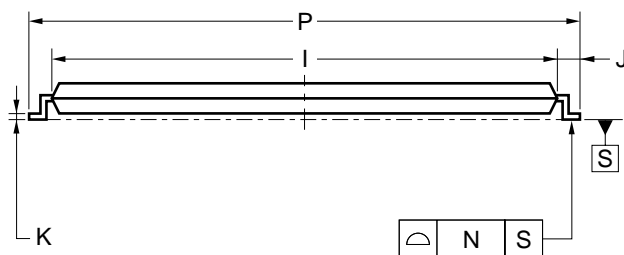
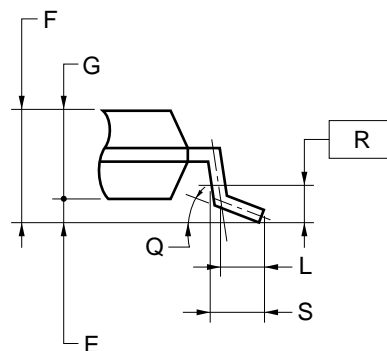
Refer to **PAGE MODE FLASH MEMORY, BURST MODE FLASH MEMORY Information (M15451E)**.

Package Drawings

48-PIN PLASTIC TSOP (I) (12x20)



detail of lead end



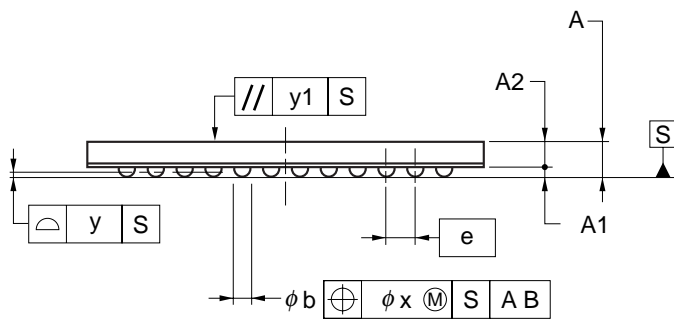
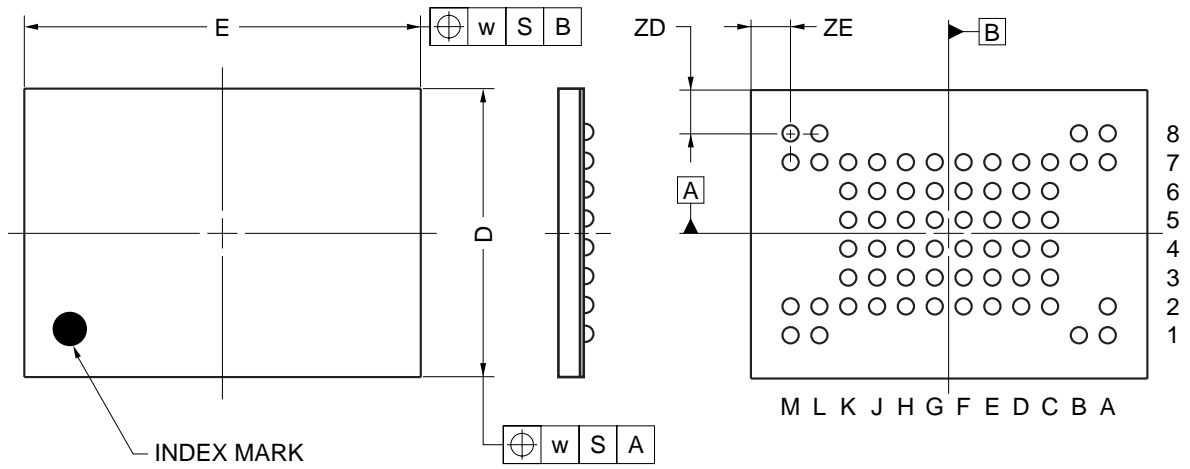
NOTES

- 1) Each lead centerline is located within 0.10 mm of its true position (T.P.) at maximum material condition.
- 2) "A" excludes mold flash. (Includes mold flash : 12.4 mm MAX.)

ITEM	MILLIMETERS
A	12.0±0.1
B	0.45 MAX.
C	0.5 (T.P.)
D	0.22±0.05
E	0.1±0.05
F	1.2 MAX.
G	1.0±0.05
I	18.4±0.1
J	0.8±0.2
K	0.145±0.05
L	0.5
M	0.10
N	0.10
P	20.0±0.2
Q	3 ^{+5°} _{-3°}
R	0.25
S	0.60±0.15

S48GZ-50-MJH-1

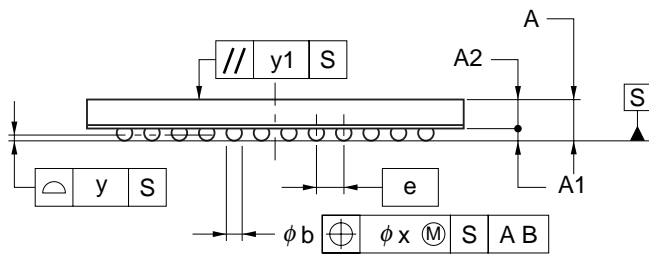
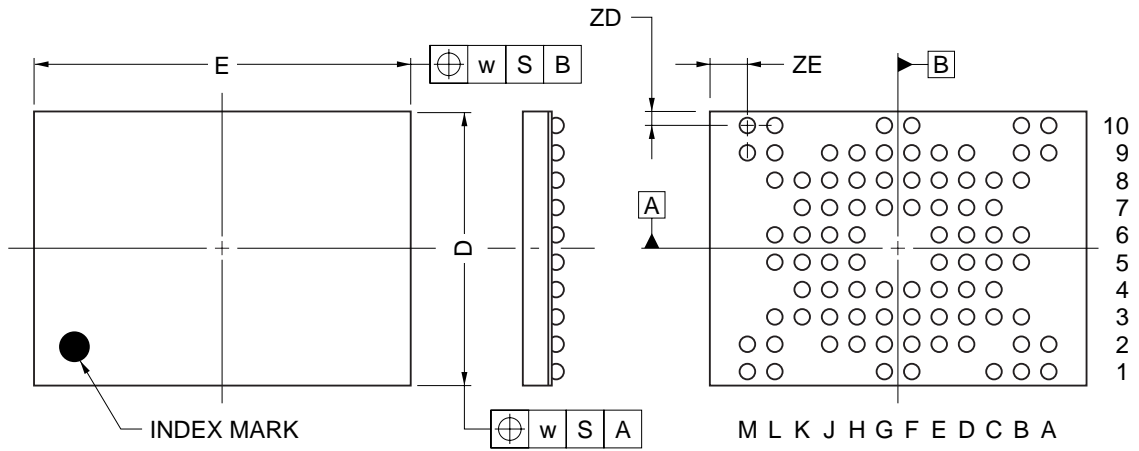
63-PIN TAPE FBGA (11x8)



ITEM	MILLIMETERS
D	8.00±0.10
E	11.00±0.10
w	0.20
A	0.97±0.10
A1	0.27±0.05
A2	0.70
e	0.80
b	0.45±0.05
x	0.08
y	0.10
y1	0.20
ZD	1.20
ZE	1.10

P63F9-80-CD6

85-PIN TAPE FBGA (11x8)



ITEM	MILLIMETERS
D	8.00±0.10
E	11.00±0.10
w	0.20
e	0.80
A	1.11±0.10
A1	0.27±0.05
A2	0.84
b	0.45±0.05
x	0.08
y	0.10
y1	0.20
ZD	0.40
ZE	1.10

P85F9-80-CD5

Recommended Soldering Conditions

Please consult with our sales offices for soldering conditions of the μ PD29F064115-X.

Types of Surface Mount Device

μ PD29F064115GZ-MJH : 48-pin PLASTIC TSOP(I) (12 × 20) (Normal bent)

μ PD29F064115F9-CD6 : 63-pin TAPE FBGA (11 × 8)

μ PD29F064115F9-CD5 : 85-pin TAPE FBGA (11 × 8)

Revision History

Edition/ Date	Page		Type of revision	Location	Description (Previous edition -> This edition)
	This edition	Previous edition			
2nd edition/ Sep.2002	Throughout	–	Modification	–	Preliminary Data Sheet → Data Sheet
	p.16	p.14		Command Sequence	Remark 2 : SPA, SUA
	p.21	p.19	Addition	Read Cycle	t _{OEH}

[MEMO]

[MEMO]

NOTES FOR CMOS DEVICES**① PRECAUTION AGAINST ESD FOR SEMICONDUCTORS**

Note:

Strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred. Environmental control must be adequate. When it is dry, humidifier should be used. It is recommended to avoid using insulators that easily build static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work bench and floor should be grounded. The operator should be grounded using wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with semiconductor devices on it.

② HANDLING OF UNUSED INPUT PINS FOR CMOS

Note:

No connection for CMOS device inputs can be cause of malfunction. If no connection is provided to the input pins, it is possible that an internal input level may be generated due to noise, etc., hence causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using a pull-up or pull-down circuitry. Each unused pin should be connected to V_{DD} or GND with a resistor, if it is considered to have a possibility of being an output pin. All handling related to the unused pins must be judged device by device and related specifications governing the devices.

③ STATUS BEFORE INITIALIZATION OF MOS DEVICES

Note:

Power-on does not necessarily define initial status of MOS device. Production process of MOS does not define the initial operation status of the device. Immediately after the power source is turned ON, the devices with reset function have not yet been initialized. Hence, power-on does not guarantee out-pin levels, I/O settings or contents of registers. Device is not initialized until the reset signal is received. Reset operation must be executed immediately after power-on for devices having reset function.

Related Document

Document Name	Document Number
PAGE MODE FLASH MEMORY, BURST MODE FLASH MEMORY Information	M15451E

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